FRONTGRADE

DATASHEET

UT54ACS86E

Quadruple 2-Input Exclusive OR Gates

1/5/2018

Version #: 1.0

Features

- 0.6µm CRH CMOS process
  - > Latchup immune
- High speed
- Low power consumption
- Wide power supply operating range from 3.0V to 5.5V
- Available QML Q or V processes
- 14-lead flatpack
- UT54ACS86E-SMD- 5962-96538

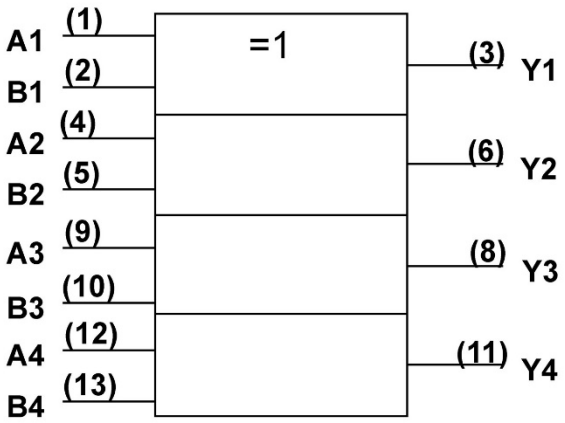
Description

The UT54ACS00E is a quadruple, two-input Exclusive OR gate. The circuits perform the Boolean functions $Y = \overline{A} \oplus \overline{B}$ or $Y = \overline{AB} + \overline{AB}$ in positive logic.

An application is as a true/complement element. If one of the inputs is low, the other input will be reproduced in true form at the output. If one of the inputs is high, the signal on the other input will be reproduced inverted at the output.

The devices is characterized over full military temperature range of -55°C to +125°C.

Logic Symbol



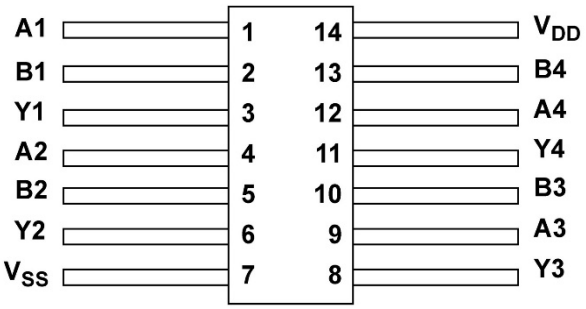
Note:

1. Logic symbol in accordance with ANSI/IEEE standard 91-1984 and IEC Publication 617-12.

Function Table

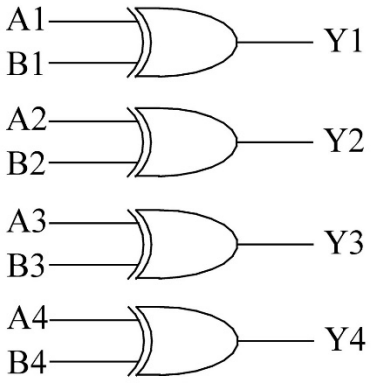
In	puts		Output
A		B	Y
L		L	L
L		H	H
H		L	H
H		H	L

Pinout



14-Lead Flatpack
Top View

Logic Diagram



Operational Environment[1]

Parameter	Limit	Units
Total Dose	1.0E6	rads(Si)
SEU Threshold[2]	108	MeV-cm²/mg
SEL Threshold	120	MeV-cm²/mg
Neutron Fluence	1.0E14	n/cm2

Notes:

1. Logic will not latchup during radiation exposure within the limits defined in the table.
2. Device storage elements are immune to SEU affects.

Absolute Maximum Ratings[1]

Symbol	Parameter	Limit	Units
V_{DD}	Supply voltage	-0.3 to 7.0	V
$V_{I/O}$	Voltage any pin	-0.3 to V_{DD} +0.3	V
T_{STG}	Storage Temperature range	-65 to +150	°C
T_J	Maximum junction temperature	+175	°C
T_{LS}	Lead temperature (soldering 5 seconds)	+300	°C
Θ_{JC}	Thermal resistance junction to case	15.0	°C/W
I_I	DC input current	±10	mA
P_D	Maximum package power dissipation permitted @ T_C = +125°C	3.2	W

Notes:

1. Stresses outside the listed absolute maximum ratings may cause permanent damage to the device. This is a stress rating only, functional operation of the device at these or any other condition beyond limits indicated in the operational sections is not recommended. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.
2. Per MIL-STD-883, method 1012.1, Section 3.4.1, PD = $(T_{j(max)} - T_{c(max)}) / \Theta_{JC}$

Recommended Operating Conditions

Symbol	Parameter	Typical	Units
V_{DD}	Supply voltage	3.0 to 5.5	V
V_{IN}	Input voltage any pin	0 to V_{DD}	V
T_C	Temperature range	-55 to + 125	°C

Electrical Characteristics for the UT54ACS86E7

(V_{DD} = 3.0V to 5.5V; V_{SS} = 0V[6]; -55°C < T_C < +125°C)

Symbol	Description		Condition	MIN	MAX	Unit
V_{IL}	Low-level input voltage[1]		V_{DD} from 3.0V to 5.5V		0.3V_{DD}	V
V_{IH}	High-level input voltage[1]		V_{DD} from 3.0V to 5.5V	0.7V_{DD}		V
I_{IN}	Input leakage current		V_{IN} = V_{DD} or V_{SS}	-1	1	µA
V_{OL1}	Low-level output voltage[3]		I_{OL} = 100µA		0.25	V
V_{OH2}	High-level output voltage[3]		I_{OH} = -100µA	V_{DD} - 0.25		V
I_{OS1}	Short-circuit output current[2,4]		V_O = V_{DD} and V_{SS} V_{DD} from 4.5V to 5.5V	-200	200	mA
I_{OS2}	Short-circuit output current[2,4]		V_O = V_{DD} and V_{SS} V_{DD} from 3.0V to 3.6V	-100	100	mA
I_{OL1}	Low level output current[9]		V_{IN} = V_{DD} or V_{SS} V_{OL} = 0.4V V_{DD} from 4.5V to 5.5V	8		mA
I_{OL2}	Low level output current[9]		V_{IN} = V_{DD} or V_{SS} V_{OL} = 0.4V V_{DD} from 3.0V to 3.6V	6		mA
I_{OH1}	High level output current[9]		V_{IN} = V_{DD} or V_{SS} V_{OH} = V_{DD}-0.4V V_{DD} from 4.5V to 5.5V	-8		mA
I_{OH2}	High level output current[9]		V_{IN} = V_{DD} or V_{SS} V_{OH} = V_{DD}-0.4V V_{DD} from 3.0V to 3.6V	-6		mA
P_{total1}	Power dissipation[2,8,10]		C_L = 50pF V_{DD} = 4.5V to 5.5V		1.0	mW/MHz
P_{total2}	Power dissipation[2,8,10]		C_L = 50pF V_{DD} from 3.0V to 3.6V		0.5	mW/MHz
I_{DDQ}	Quiescent Supply Current	Pre-Rad All Device Types	V_{IN} = V_{DD} or V_{SS} V_{DD}=V_{DD} MAX		10	µA
		Post-Rad Device Type - 03			50	
		Post-Rad Device Type - 02			130	
C_{OUT}	Output capacitance[5]		ƒ = 1MHz V_{DD} = 0V		15	pF
C_{IN}	Input capacitance[5]		ƒ = 1MHz V_{DD} = 0V		15	pF

Notes:

1. Functional tests are conducted in accordance with MIL-STD-883 with the following input test conditions: $V_{IH} = V_{IH}$ (min) + 20%, - 0%; $V_{IL} = V_{IL}$(max) + 0%, - 50%, as specified herein, for TTL, CMOS, or Schmitt compatible inputs. Devices may be tested using any input voltage within the above specified range, but are guaranteed to V_{IH}(min) and VIL(max).
2. Supplied as a design limit but not guaranteed or tested.
3. Per MIL-PRF-38535, for current density ≤ 5.0E5 amps/cm^2, the maximum product of load capacitance (per output buffer) times frequency should not exceed 3,765 pF/MHz.
4. Not more than one output may be shorted at a time for maximum duration of one second.
5. Capacitance measured for initial qualification and when design changes may affect the value. Capacitance is measured between the designated terminal and V_{SS} at frequency of 1MHz and a signal amplitude of 50mV rms maximum.
6. Maximum allowable relative shift equals 50mV.
7. Device type 02 is only offered with a TID tolerance guarantee of 3E5 rads(Si) or 1E6 rads(Si), and is tested in accordance with MIL-STD-883 Test Method 1019 Condition and section 3.11.2. Device type 03 is only offered with a TID tolerance guarantee of 1E5 rads(Si), 3E5 rads(Si), and 5E5 rads(Si), and is tested in accordance with MIL-STD-883 Test Method 1019 Condition A.
8. Power dissipation specified per switching output.
9. Guaranteed by characterization, but not tested.
10. Power does do not include power contribution of any TTL output sink current.

AC Electrical Characteristics for the UT54ACS86E[2]

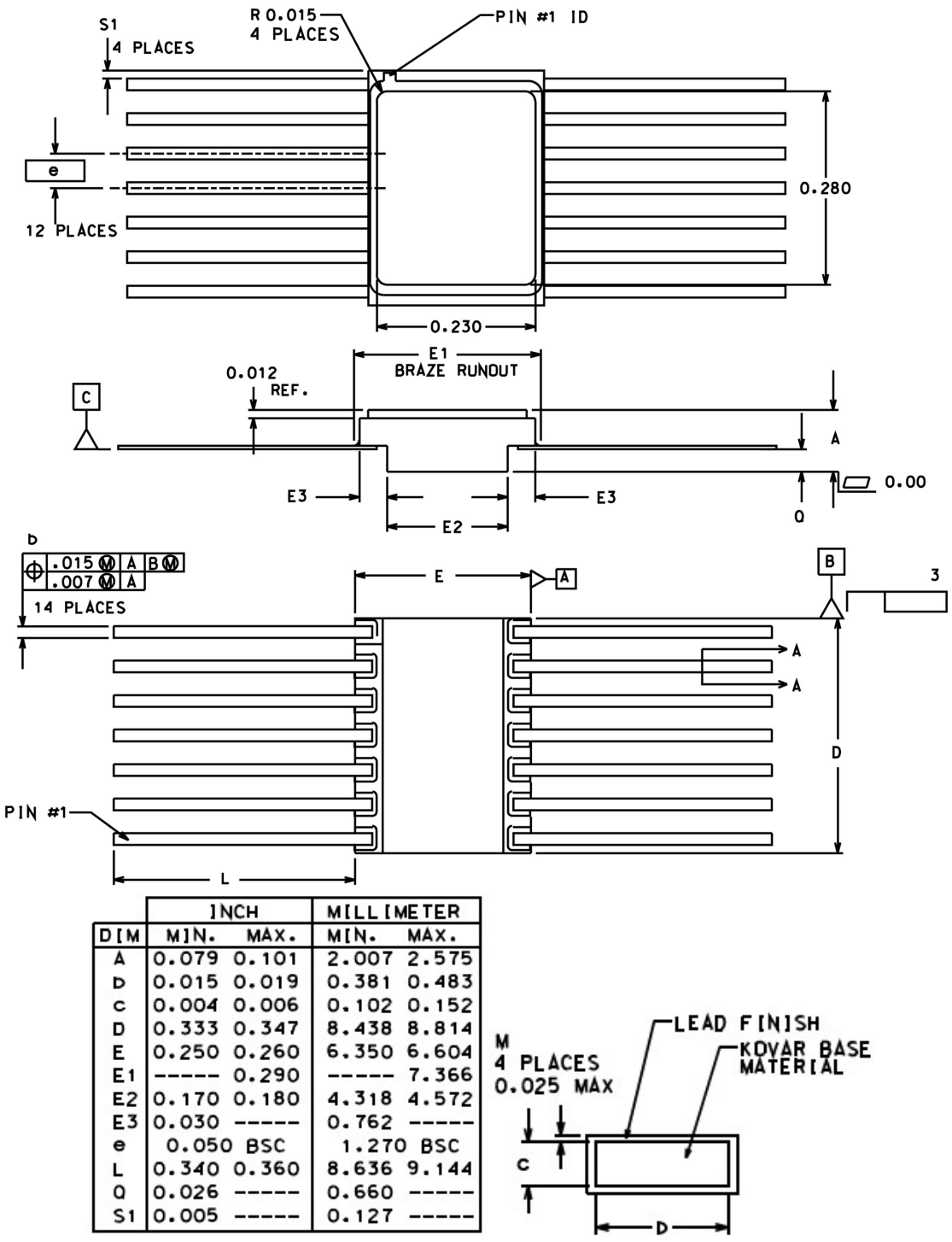
(V_{DD}= 3.0V to 5.5V; V_{SS}= 0V[1]; -55°C < T_C < +125°C)

Symbol	Parameter	Condition	V_{DD}	Minimum	Maximum	Unit
t_{PLH}	Input to Yn	CL = 50pF	4.5V to 5.5V	1	6.5	ns
			3.0V to 3.6V	1	9.0	
t_{PHL}	Input to Yn	CL = 50pF	4.5V to 5.5V	1	7.5	ns
			3.0V to 3.6V	1	9.5	

Notes:

1. Maximum allowable relative shift equals 50mV.
2. Device type 02 is only offered with a TID tolerance guarantee of 3E5 rads(Si) or 1E6 rads(Si), and is tested in accordance with MIL-STD-883 Test Method 1019 Condition A and section 3.11.2. Device type 03 is only offered with a TID tolerance guarantee of 1E5 rads(Si), 3E5 rads(Si), and 5E5 rads(Si), and is tested in accordance with MIL-STD-883 Test Method 1019 Condition A.

Packaging



DIM	INCH MIN.	INCH MAX.	MILLIMETER MIN.	MILLIMETER MAX.
A	0.079	0.101	2.007	2.575
b	0.015	0.019	0.381	0.483
c	0.004	0.006	0.102	0.152
D	0.333	0.347	8.438	8.814
E	0.250	0.260	6.350	6.604
E1	-----	0.290	-----	7.366
E2	0.170	0.180	4.318	4.572
E3	0.030	-----	0.762	-----
e	0.050 BSC		1.270 BSC	
L	0.340	0.360	8.636	9.144
Q	0.026	-----	0.660	-----
S1	0.005	-----	0.127	-----

Figure 1. 14-Lead Flatpack

Notes:

1. All exposed metallized areas are gold plated over electroplated nickel per MIL-PRF-38535.
2. The lid is electrically connected to V_{SS}.
3. Lead finishes are in accordance with MIL-PRF-38535.
4. Dimension symbol is in accordance with MIL-PRF-38533.
5. Lead position and colanarity are not measured.

Ordering Information: UT54ACS86E: SMD

SMD Part Number Ordering Information

5962 * ***** ** * * *

Lead Finish: (Notes: 1, 2)
(A) = Solder
(C) = Gold
(X) = Optional

Package Type:
(X) = 14-lead Ceramic Bottom-Brazed Dual-in-line Flatpack

Class Designator:
(Q) = QML Class Q
(V) = QML Class V

Device Type:
(02) = 1 rad(Si)/sec
(03) = 50-300 rad(Si)/sec

Drawing Number:
(96538) = UT54ACS86E

Total Dose: (Notes: 3, 4)
(R) = 1E5 rads(Si)
(F) = 3E5 rads(Si)
(G) = 5E5 rads(Si)
(H) = 1E6 rads(Si)

Federal Stock Class Designator

Notes:

1. Lead finish (A, C, or X) must be specified.
2. If an "X" is specified when ordering, part marking will match the lead finish and will be either "A" (solder) or "C" (gold).
3. Total dose radiation must be specified when ordering. QML Q and QML V not available without radiation hardening. For prototype inquiries, contact factory.
4. Device type 02 is only offered with a TID tolerance guarantee of 3E5 rads(Si) or 1E6 rads(Si) and is tested in accordance with MIL-STD-883 Test Method 1019 Condition A and section 3.11.2. Device type 03 is only offered with a TID tolerance guarantee of 1E5 rads(Si), 3E5 rads(Si), and 5E5rads(Si), and is tested in accordance with MIL-STD-883 Test Method 1019 Condition A.

Revision History

Date	Revision #	Author	Change Description	Page #
10/17		RT	Edited IDDQ Applied new CAES Data Sheet template to the document.	4
1/18		RT	Updates to reflect current SMD	8

Datasheet Definitions

	Definition
Advanced Datasheet	Frontgrade reserves the right to make changes to any products and services described herein at any time without notice. The product is still in the development stage and the **datasheet is subject to change**. Specifications can be **TBD** and the part package and pinout are **not final.**
Preliminary Datasheet	Frontgrade reserves the right to make changes to any products and services described herein at any time without notice. The product is in the characterization stage and prototypes are available.
Datasheet	Product is in production and any changes to the product and services described herein will follow a formal customer notification process for form, fit or function changes.